Search Notes



| Application/Control No. | Applicant(s)/Patent Under Reexamination | |
|-------------------------|---|--|
| 10697108 | BEISEL ET AL. | |
| Examiner | Art Unit | |
| Lee, Siu M | 2611 | |

| SEARCHED | | | | | |
|----------|----------|-----------|------------|--|--|
| Class | Subclass | Date | Examiner | | |
| 375 | 224, 316 | 2/17/2007 | Siu M. Lee | | |
| 398 | 1-8 | 2/17/2007 | Siu M. Lee | | |
| 370 | 217-229 | 2/17/2007 | Siu M. Lee | | |

| SEARCH NOTES | | | | | |
|--|-----------|------------|--|--|--|
| Search Notes | Date | Examiner | | | |
| EAST | 2/17/2007 | Siu M. Lee | | | |
| Discuss the application with Cheih Fan | 2/17/2007 | Siu M. Lee | | | |

| INTERFERENCE SEARCH | | | | | |
|---------------------|----------|------|----------|--|--|
| Class | Subclass | Date | Examiner | | |
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